

Special Issue

New Applications of (Old School) Projective Geometry

Message from the Guest Editor

In this Special Issue, we encourage submissions presenting new results in or providing an inspiring overview of technological applications of projective geometry in fields belonging but not restricted to the following list:

- Computer vision: alternative calibration for classical models (spheres, incidence patterns, etc.) and general cameras (line congruences, etc.), 3D modeling and reconstruction (line interpolations, etc.), multicamera configurations, etc.;
- Robot kinematics, singularity analysis, rigidity of structures, etc.;
- Algebra of mechanics and computer vision performed in synthetic environments such as the bracket algebra, Grassmann algebra, etc.;
- Other engineering branches such as quantum mechanics, laser and nano technology, etc.

Guest Editor

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Deadline for manuscript submissions

closed (15 February 2022)



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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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